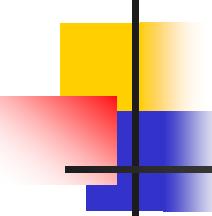


Very Large Scale Integration (VLSI)

Lecture 3

Dr. Ahmed H. Madian

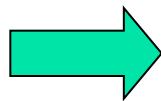
Ah_madian@hotmail.com



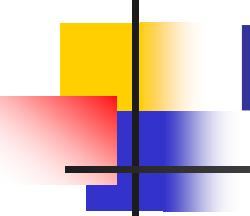
Contents

- 
- Wiring tracks
 - Latch-up
 - Circuit characterization & performance
 - Resistance estimation
 - Capacitance estimation
 - Inductance estimation
 - Delay estimation
 - Simple RC model
 - Penfield-Rubenstein Model
 - Delay minimization techniques
 - Transistor sizing
 - Distributed drivers
 - Large driver
 - Wiring techniques

Circuit characterization & performance



- Resistance estimation
- Capacitance estimation
- Inductance estimation



Parasitic Elements

- So far, we've concentrated on getting circuit elements that we want for digital design
 - Transistors
 - Wires
- **Parasitics** - occur whether we want them or not
 - Capacitors
 - Resistors
 - Transistors (bipolar and FET)

Resistance estimation

- Resistance of uniform slab can be given as,

$$R = \frac{\rho}{t} \cdot \frac{l}{w} \text{ ohms}$$

Where ρ = resistivity

t = thickness

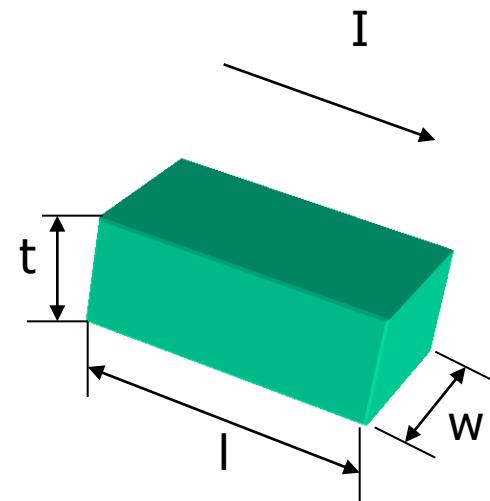
l = conductor length

w =conductor width

or,

$$R = R_s \cdot \frac{l}{w} \text{ ohms}$$

R_s is the sheet resistance Ω/\square



Resistance estimation (cont.)

- Resistance of certain layers

Material	R_s (Ω/\square)
metal	0.03
Poly	15 → 100
Diffusion p	80
Diffusion n	35
Silicide	2 → 4
N-well	1K → 5K

Resistance estimation

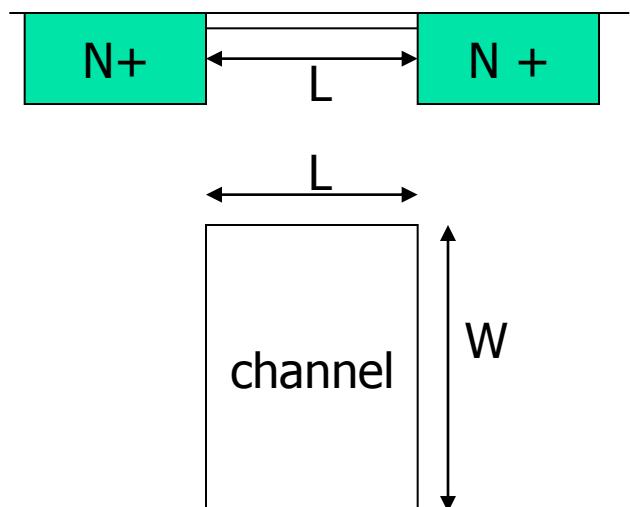
- For MOSFET channel resistance

$$R_{\text{channel}} = R_{\text{Sheet}} (L/W)$$

where $R_{\text{sheet}} = 1/\mu C_{\text{OX}}(V_{\text{gs}} - V_t)$

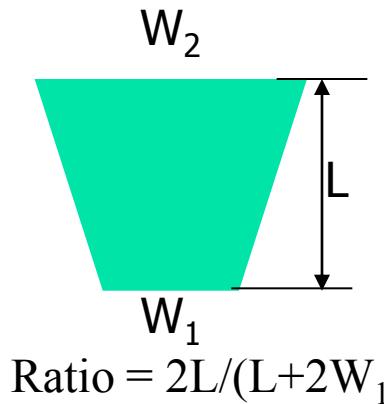
For P and n channels

$$R_{\text{sheet}} = 1000 \rightarrow 30,000 \Omega/\square$$

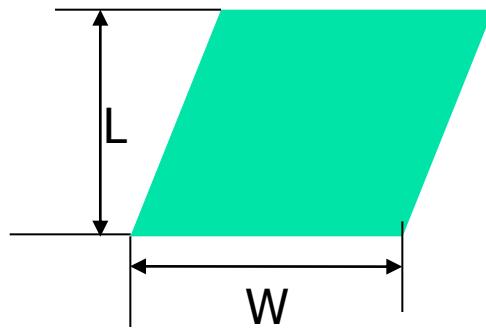


Resistance estimation (cont.)

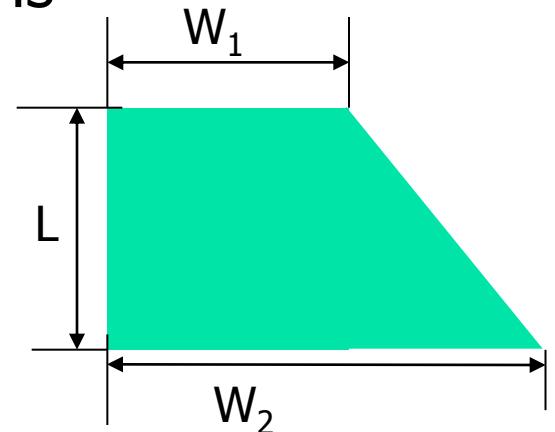
Resistance of non rectangular regions



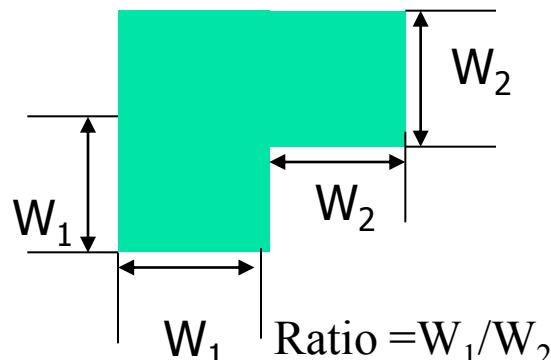
$$\text{Ratio} = 2L/(L+2W_1)$$



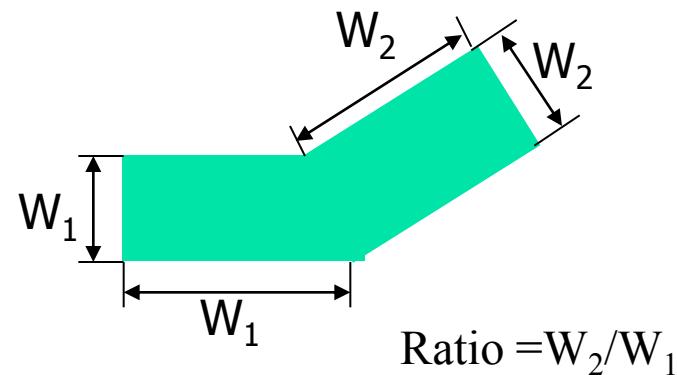
$$\text{Ratio} = L/W$$



$$\text{Ratio} = L/W$$



$$\text{Ratio} = W_1/W_2$$



$$\text{Ratio} = W_2/W_1$$

Resistance

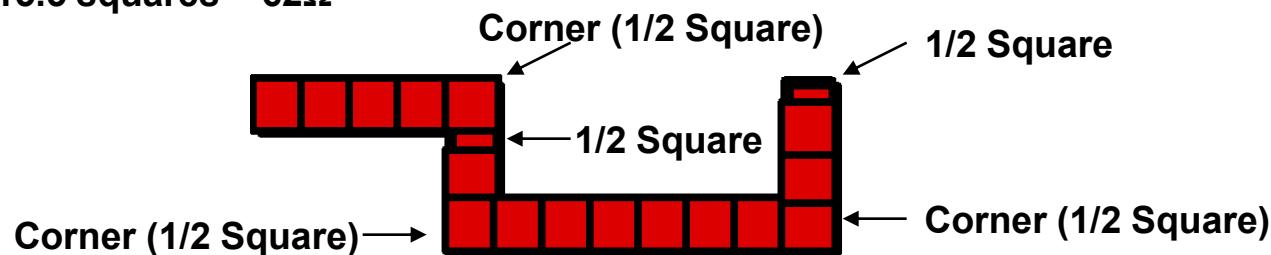
- Depends on resistivity of material ρ (Rho)
- Sheet resistance $R_s = \rho / t$
- Resistance $R = R_s * L / W$
- Corner approximation - count a corner as half a square



Example:

$$R = R_{s(\text{poly})} * 13 + 2*(1/2) + 3*(1/2) \text{ squares}$$

$$R = 4\Omega/\text{sq} * 15.5 \text{ squares} = 62\Omega$$



Inverter resistance estimation

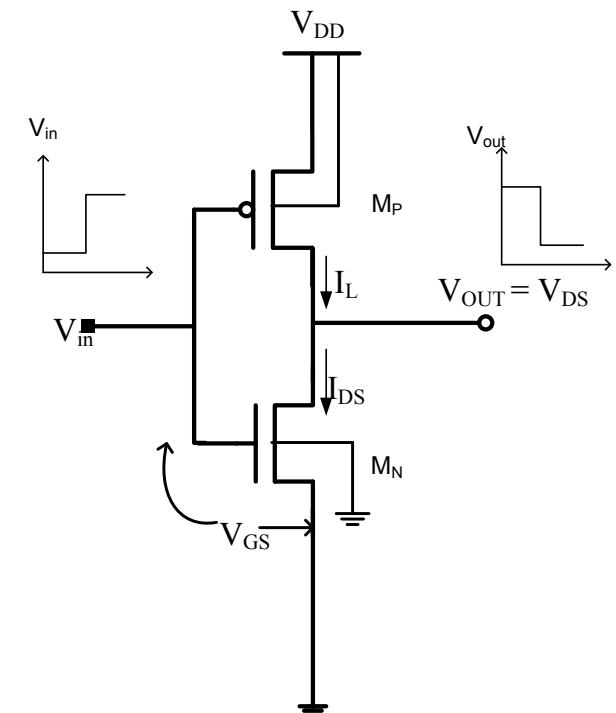
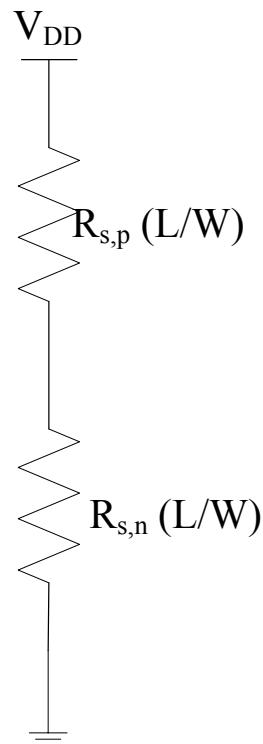
- CMOS inverter (no static current)
- Switching current

$$I_{\max} = \frac{V_{DD}}{R_{total}} = \frac{V_{DD}}{R_{s,p} \frac{L}{W} + R_{s,n} \frac{L}{W}}$$

for $L = W = 1$

$$I_{\max} = \frac{V_{DD}}{R_{s,p} + R_{s,n}} = \frac{V_{DD}}{25 + 10} = \frac{V_{DD}}{35}$$

$$\text{switching power loss} = I_{\max} \cdot V_{DD} = \frac{V_{DD}^2}{35}$$



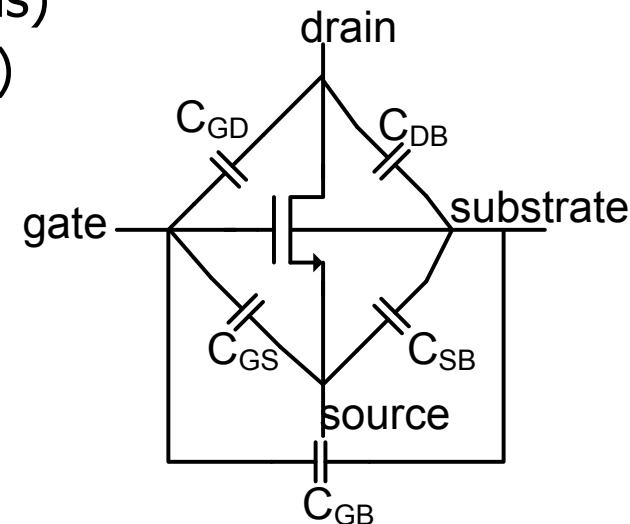
Circuit characterization & performance

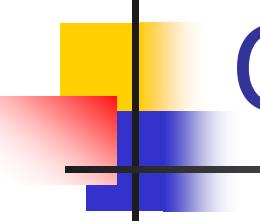
- Resistance estimation
- ■ Capacitance estimation
 - Transistor capacitance
 - Routing capacitance
- Inductance estimation
- Delay estimation

Capacitance estimation

The dynamic response of MOS systems strongly depends on the parasitic capacitances associated with the MOS device. The total load capacitance on the output of a CMOS gate is the sum of:

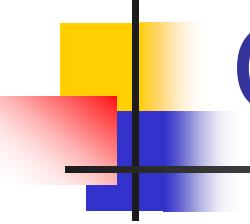
- **gate** capacitance (of other inputs connected to out)
- **diffusion** capacitance (of drain/source regions)
- **routing** capacitances (output to other inputs)





Capacitance (1/2)

- Transistors
 - Depends on area of transistor gate
 - Depends on physical materials, thickness of insulator
 - Given for a specific process as C_g
- Diffusion to substrate
 - **Side-wall capacitance** - capacitance from periphery
 - **bottom-wall capacitance** - capacitance to substrate
 - Given for a specific process as $C_{\text{diff,bot}}$, $C_{\text{diff,side}}$

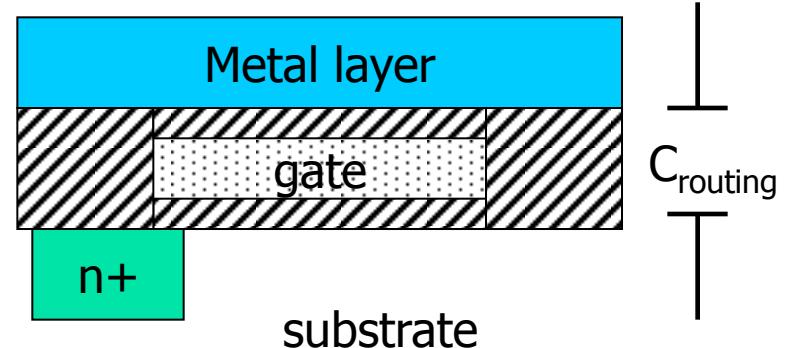
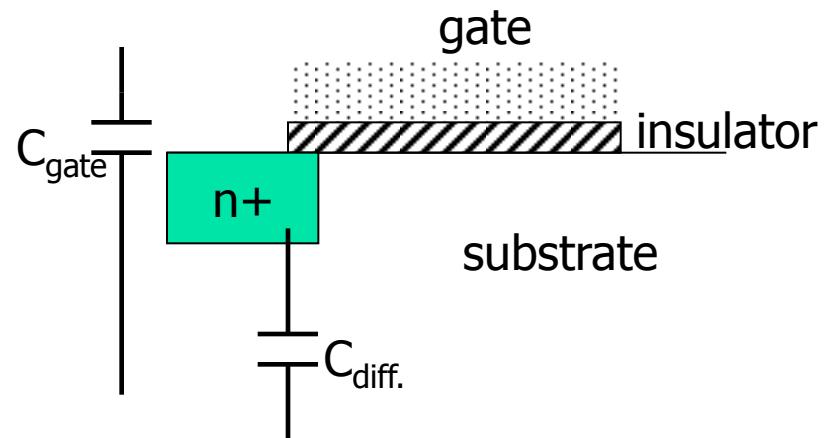


Capacitance (2/2)

- Metal to substrate
 - Parallel plate capacitance is dominant
 - Need to account for fringing, too
- Poly to substrate
 - Parallel plate plus fringing, like metal
 - don't confuse poly over substrate with gate capacitance
- Also important: capacitance between conductors
 - Metal1-Metal1
 - Metal1-Metal2

Capacitance estimation (cont.)

- Gate capacitance
 - Diffusion capacitance
 - Routing capacitance
-
- $C_{\text{diff}} > C_{\text{poly}} > C_{m1} > C_{m2}$

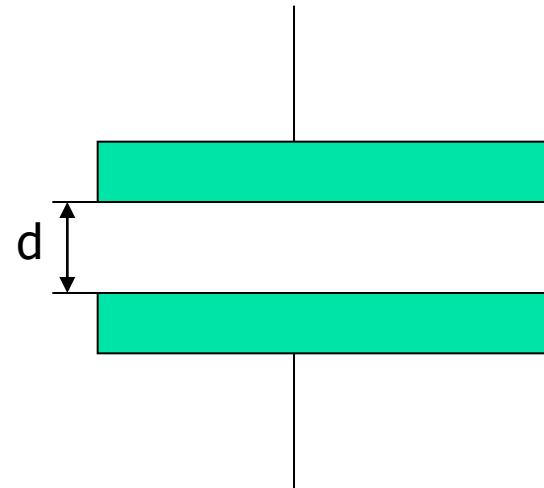


Capacitance estimation

- In general, capacitance could be calculated using

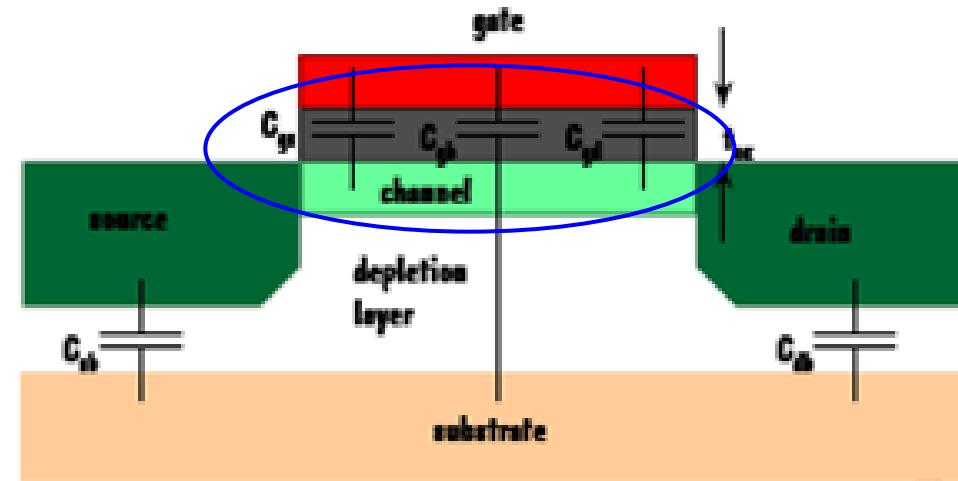
$$C = \frac{\epsilon \cdot A}{d} = \frac{\epsilon_o \cdot \epsilon_r \cdot A}{d}$$

$$C_{\text{unitarea}} = \frac{\epsilon_o \cdot \epsilon_r}{d} = C_{ox}$$



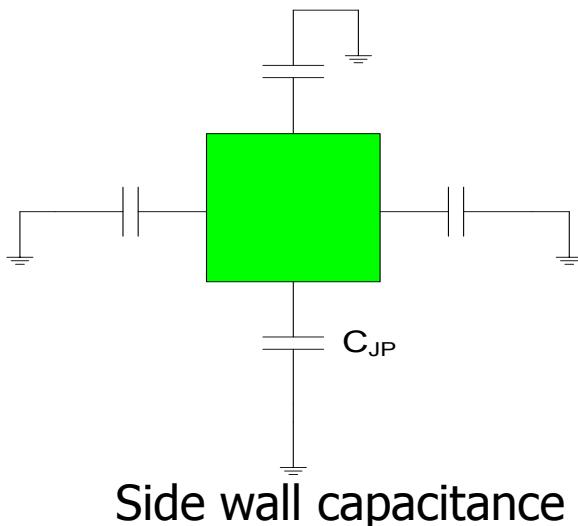
Gate Capacitance

- $C_g = C_{gs} + C_{gd} + C_{gb}$

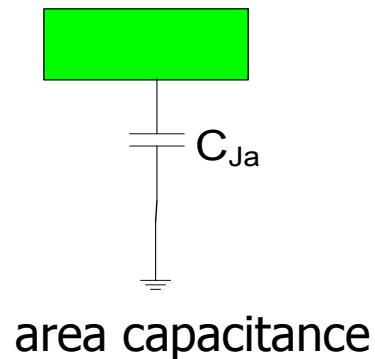


Capacitance estimation (cont.)

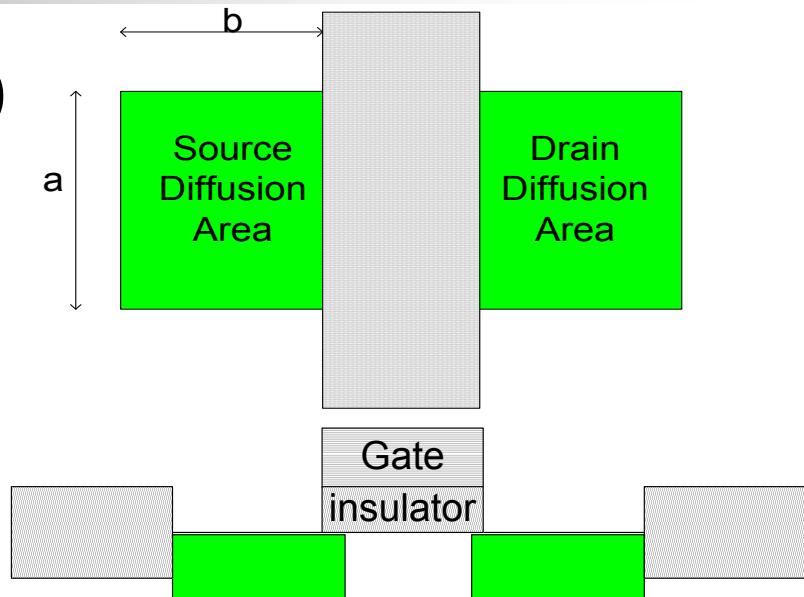
- Diffusion capacitance (source/drain)



Side wall capacitance

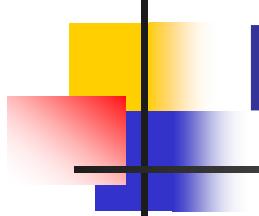


area capacitance



$$C_{s,diff} = C_{d,Area} \cdot A + C_{d,sidewalls} \cdot P$$

Where A = area and p = perimeters

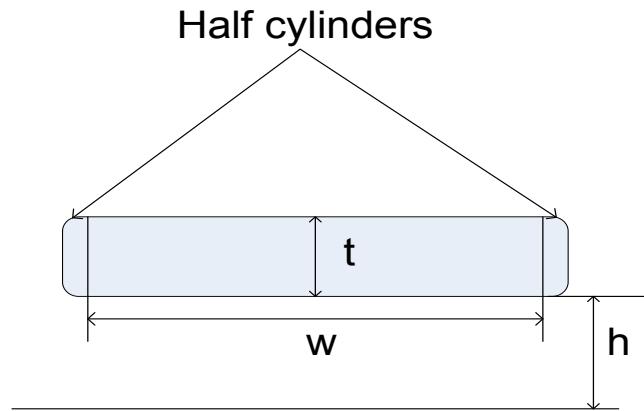
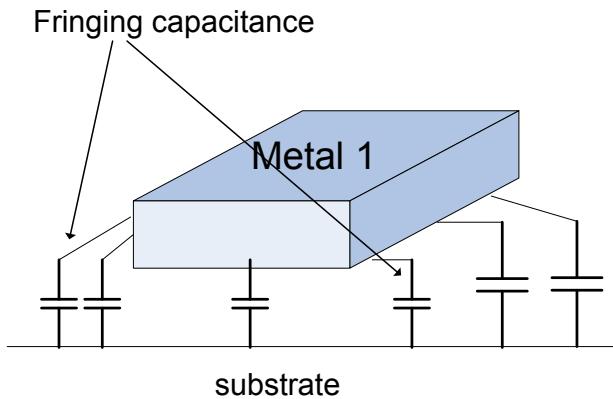


Routing capacitance

- single conductor capacitance
- multiple conductor capacitance

Capacitance estimation (cont.)

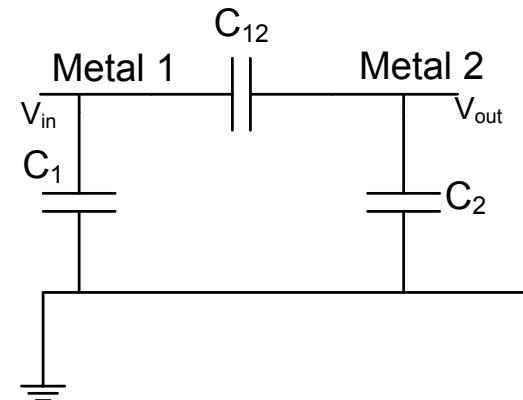
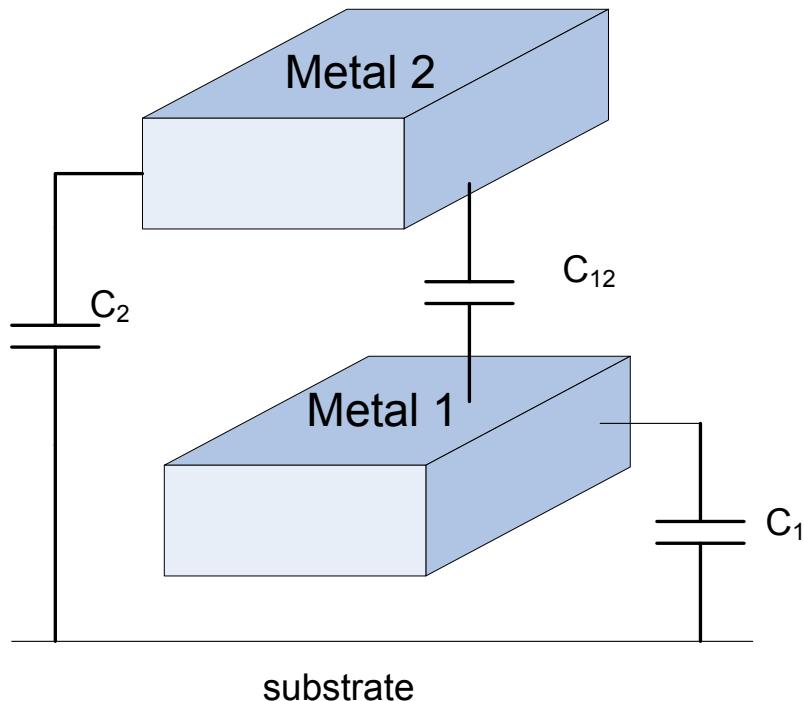
Routing capacitance: a) single conductor capacitance



$$C_{total} = \epsilon \left[\frac{w - \frac{t}{2}}{h} + \frac{2\pi}{\ln \left[1 + \frac{2h}{t} + \sqrt{\frac{2h}{t} \left[\frac{2h}{t} + 2 \right]} \right]} \right]$$

Capacitance estimation (cont.)

Routing capacitance: b) multiple conductor capacitance



$$\Delta V_{out} = \Delta V_{in} \cdot \frac{C_{12}}{C_2 + C_{12}}$$

Multilayer capacitance calculations

- Example: given the layout shown in the figure calculate the total capacitance at source and gate given that:

$$C_{\text{metal/Area}} = 0.025 \mu\text{F}/\mu\text{m}^2$$

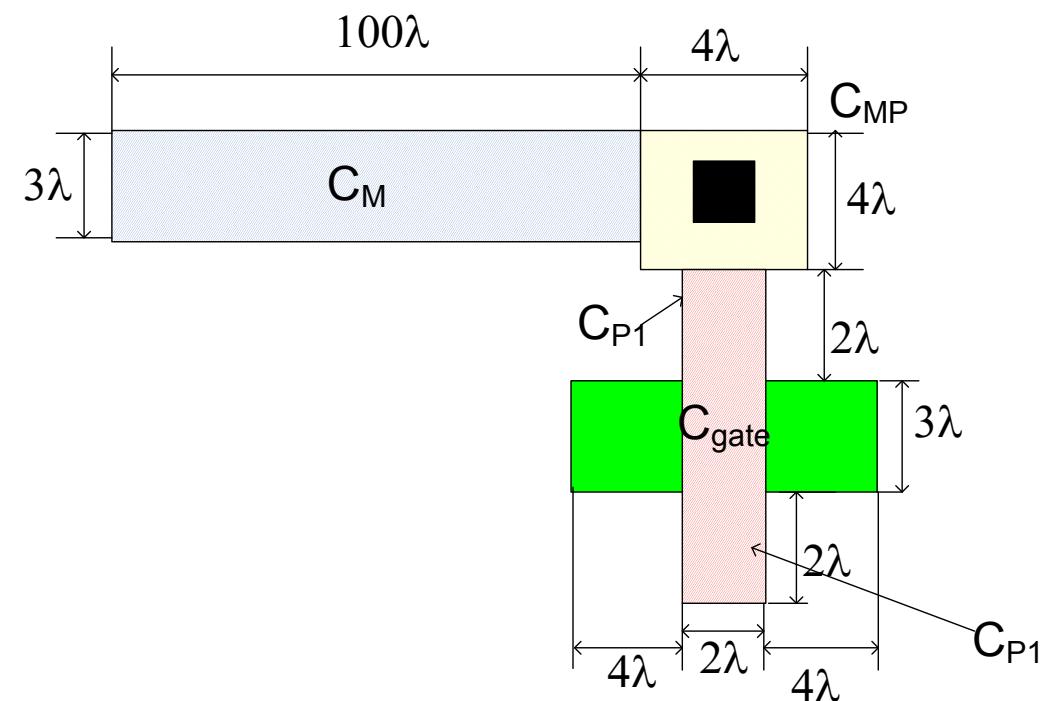
$$C_{\text{poly/Area}} = 0.045 \mu\text{F}/\mu\text{m}^2$$

$$C_{\text{Gate/A}} = 0.7 \text{ fF}/\mu\text{m}^2$$

$$C_{d,a/A} = 0.33 \text{ fF}/\mu\text{m}^2$$

$$C_{d,\text{side/L}} = 2.6 \text{ fF}/\mu\text{m}$$

$$\lambda = 5.1 \mu\text{m}$$



Solution

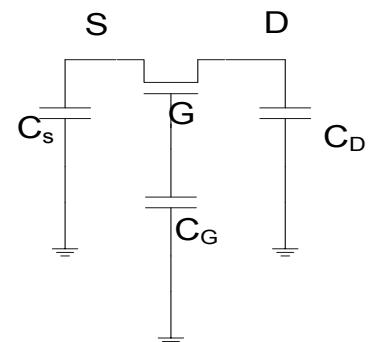
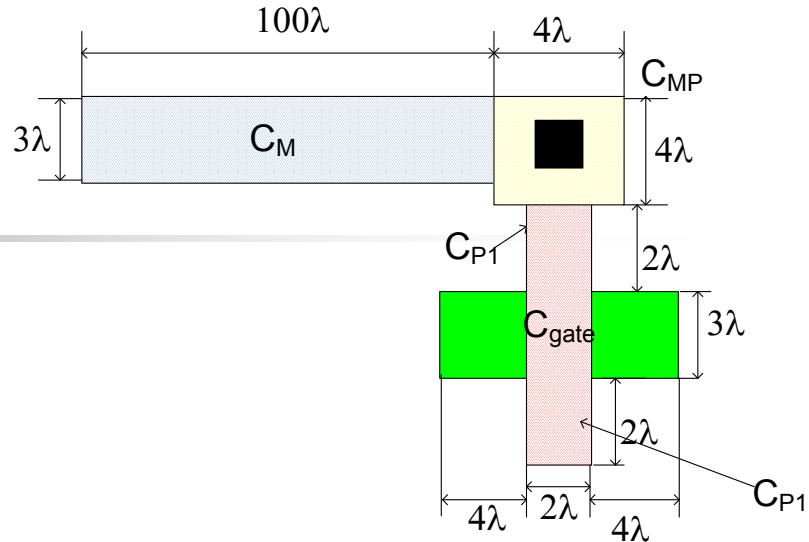
Source capacitance

$$C_{S,\text{diff}} = C_{d,A} \cdot A + C_{d,\text{side walls}} \cdot P$$

$$A = 4\lambda * 3\lambda = 12 \lambda^2$$

$$P = 2*(4\lambda + 3\lambda) = 14 \lambda$$

$$\text{So, } C_{S,\text{diff}} = 0.33 * 12 \lambda^2 + 2.6 * 14 \lambda = 63.51 \text{ fF}$$



Solution (cont.)

Gate capacitance

$$C_{G,\text{total}} = C_M + C_{MP} + C_{P1} + C_G + C_{P2}$$

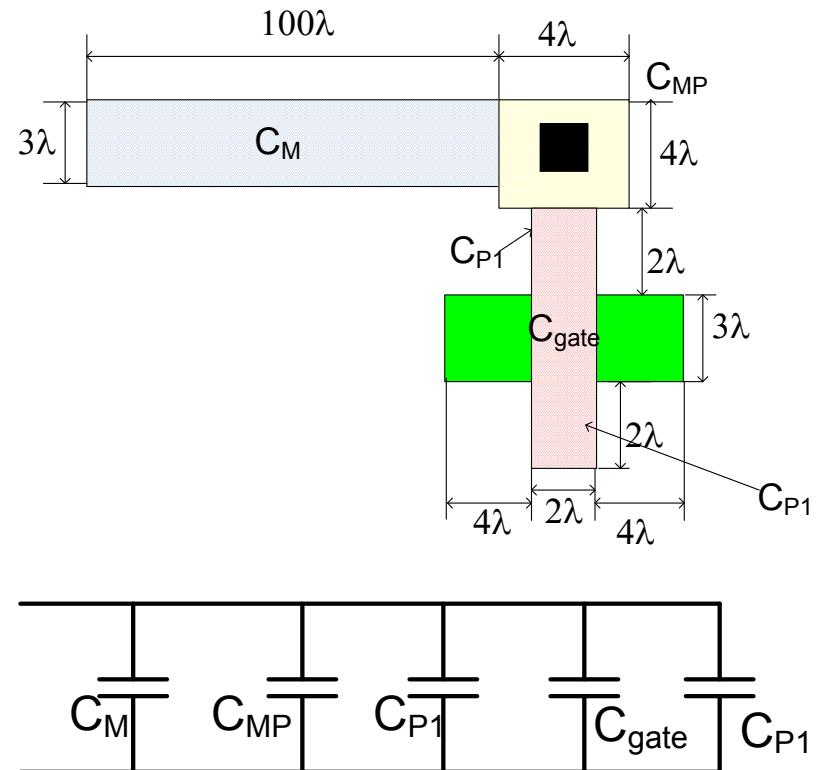
$$C_M = 0.025 * 100\lambda * 3\lambda = 7.5\lambda^2$$

$$C_{MP} = 0.045 * 4\lambda * 4\lambda = 0.72\lambda^2$$

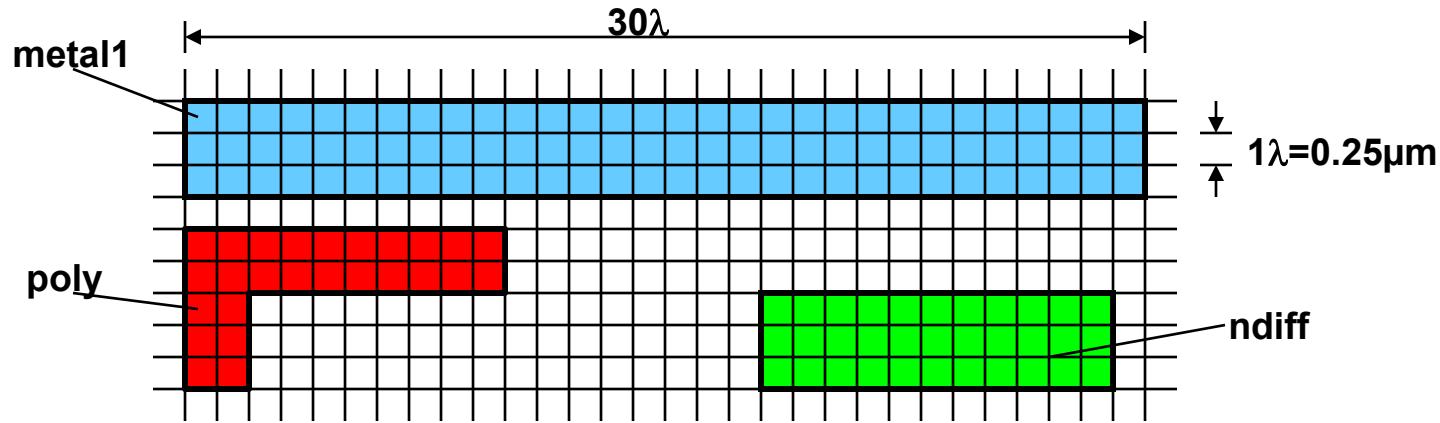
$$C_{P1} = 0.045 * 2\lambda * 2\lambda = 0.18\lambda^2$$

$$C_{P2} = 0.045 * 2\lambda * 2\lambda = 0.18\lambda^2$$

$$C_G = 0.7 * 2\lambda * 3\lambda = 4.2\lambda^2$$



Example Problems - Parasitic Calculation (1/10)



Rmetal1=?

Cmetal1=?

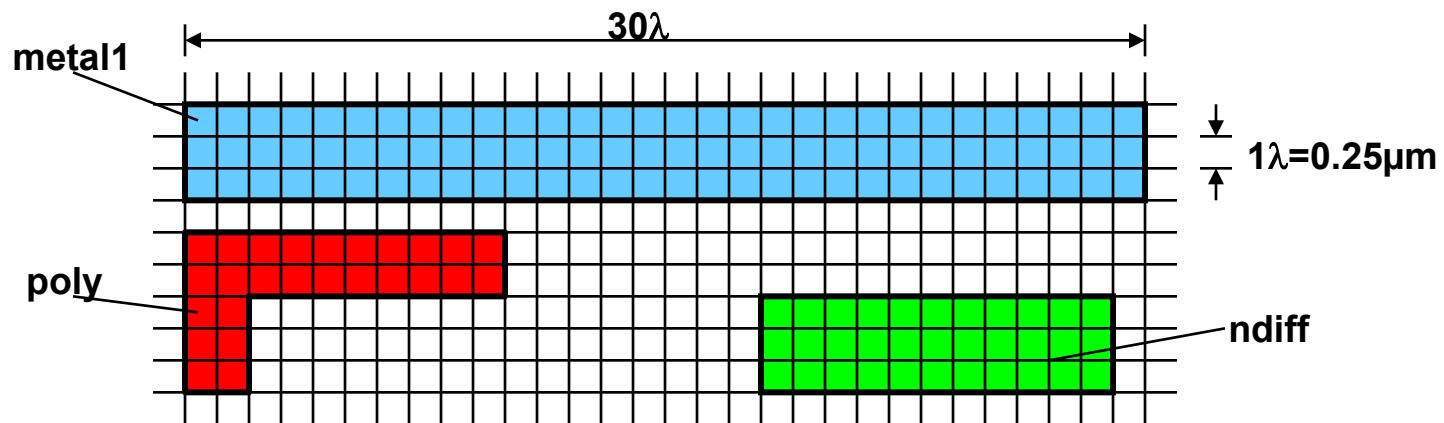
Rpoly=?

Cpoly=?

Rndiff=?

Cndiff=?

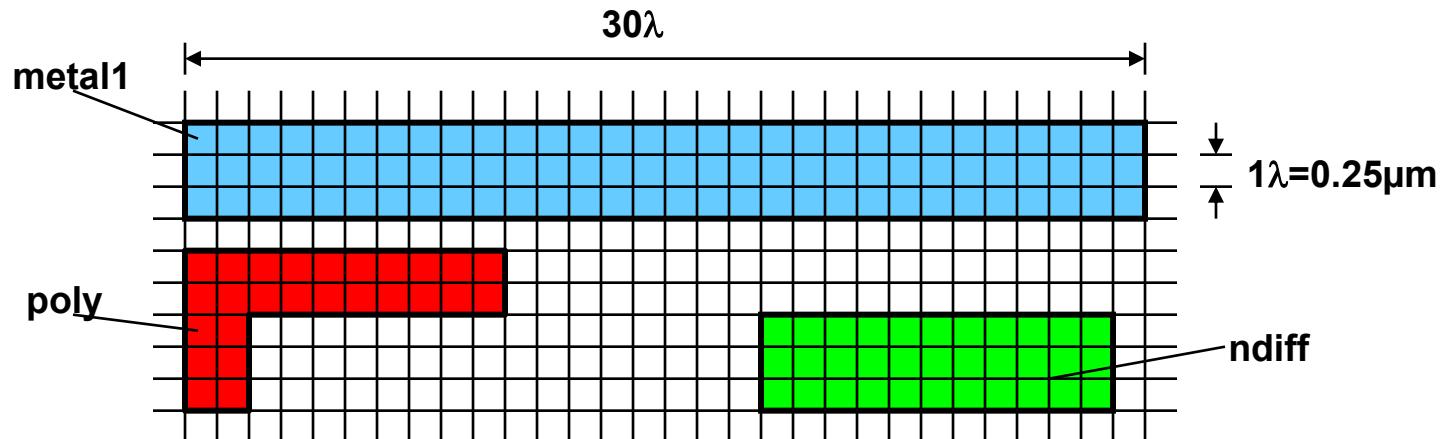
Example Problems - Parasitic Calculation (2/10)



$$R_{\text{metal1}} = (30\lambda / 3\lambda) * 0.08\Omega/\square = 0.8\Omega$$

$$\begin{aligned} C_{\text{metal1}} &= (30\lambda * 0.25\mu\text{m}/\lambda) * (3\lambda * 0.25\mu\text{m}/\lambda) * 0.04\text{fF}/\mu\text{m}^2 + \\ &\quad (30\lambda + 3\lambda + 30\lambda + 3\lambda) * 0.25\mu\text{m}/\lambda * 0.09\text{fF}/\mu\text{m} \\ &= 0.225\text{fF} + 1.485\text{fF} \\ &= 1.71\text{fF} \end{aligned}$$

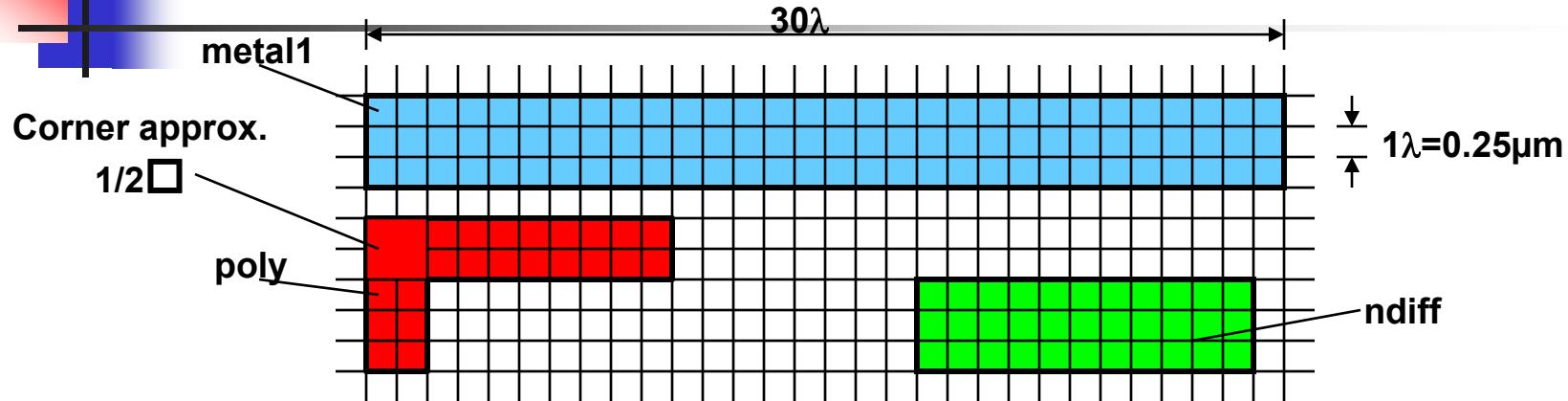
Example Problems - Parasitic Calculation (3/10)



$$R_{ndiff} = (11\lambda / 3\lambda) * 2\Omega/\square = 7.33\Omega$$

$$\begin{aligned} C_{ndiff} &= (11\lambda * 0.25\mu\text{m}/\lambda) * (3\lambda * 0.25\mu\text{m}/\lambda) * 0.6\text{fF}/\mu\text{m}^2 + \\ &\quad (11\lambda + 3\lambda + 11\lambda + 3\lambda) * 0.25\mu\text{m}/\lambda * 0.2\text{fF}/\mu\text{m} \\ &= 1.24\text{fF} + 1.4\text{fF} \\ &= 2.64\text{fF} \end{aligned}$$

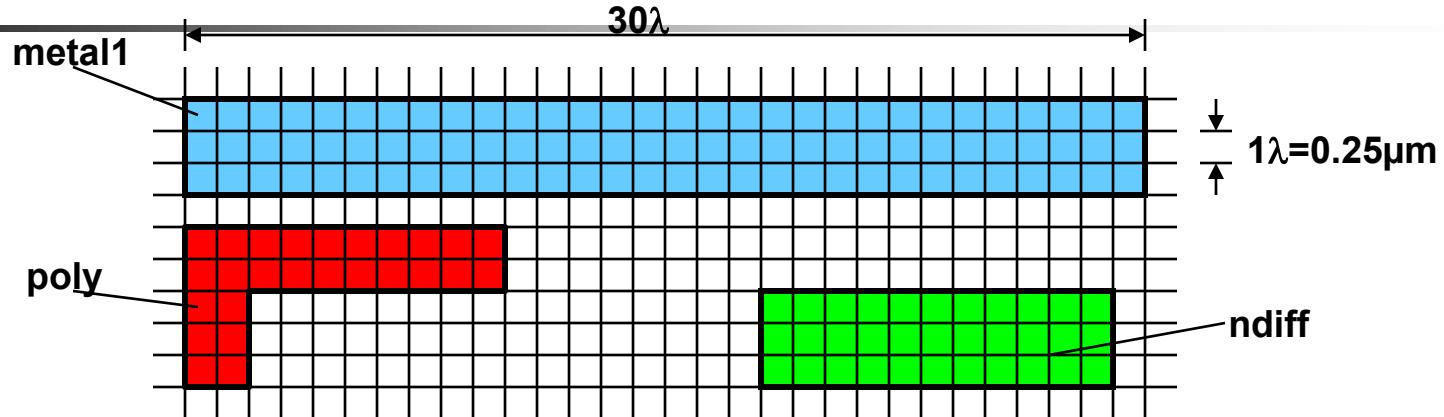
Example Problems - Parasitic Calculation (4/10)



$$R_{poly} = ((3\lambda / 2\lambda) + 1/2\square + (8\lambda / 2\lambda)) * 4\Omega/\square = 24\Omega$$

$$\begin{aligned} C_{poly} &= ((3\lambda * 0.25\mu m/\lambda) * (2\lambda * 0.25\mu m/\lambda)) + \\ &\quad ((10\lambda * 0.25\mu m/\lambda) * (2\lambda * 0.25\mu m/\lambda)) * 0.09fF/\mu m^2 + \\ &\quad (5\lambda + 10\lambda + 2\lambda + 8\lambda + 3\lambda + 2\lambda) * 0.25\mu m/\lambda * 0.04fF/\mu m \\ &= 0.15fF + 0.3fF \\ &= 0.45fF \end{aligned}$$

Example Problems - Parasitic Calculation (5/10)



$$R_{\text{metal1}} = 0.8\Omega$$

$$C_{\text{metal1}} = 1.71\text{fF}$$

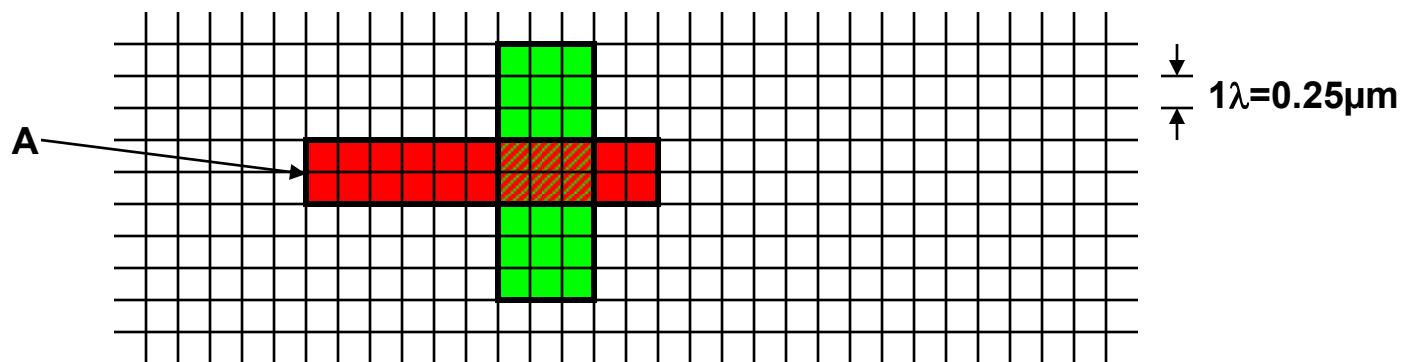
$$R_{\text{ndiff}} = 7.33\Omega$$

$$C_{\text{ndiff}} = 2.64\text{fF}$$

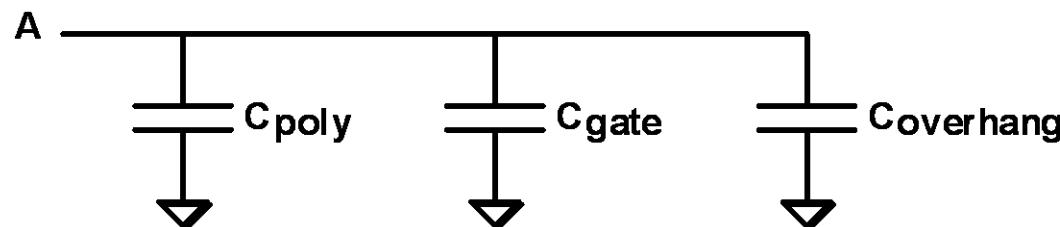
$$R_{\text{poly}} = 24\Omega$$

$$C_{\text{poly}} = 0.45\text{fF}$$

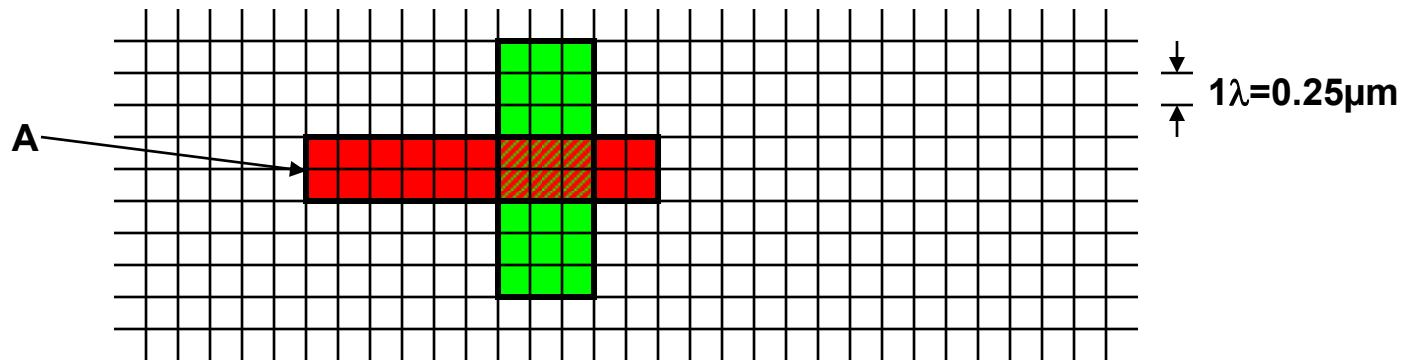
Example Problems - Parasitic Calculation (6/10)



What are the parasitic capacitances visible from point “A”?



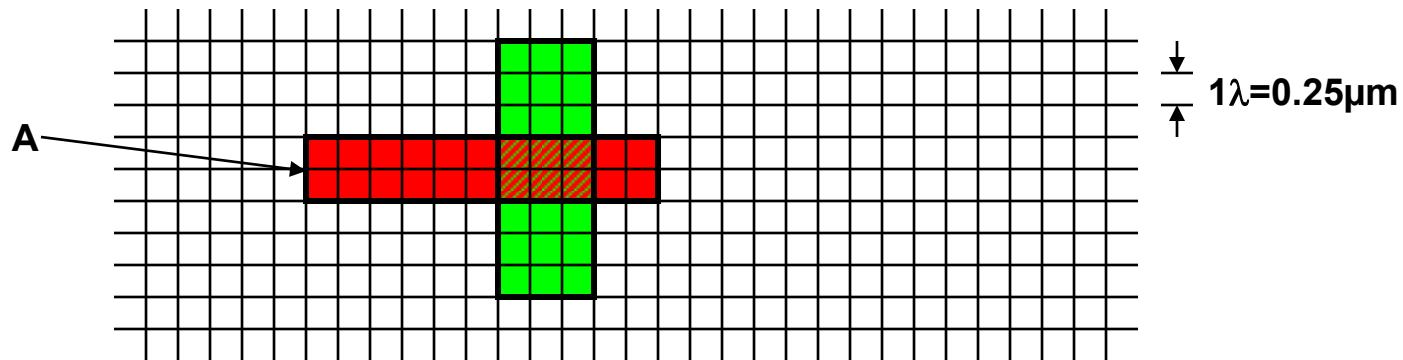
Example Problems - Parasitic Calculation (7/10)



What are the parasitic capacitances visible from point “A”?

$$\begin{aligned} C_{poly} &= (6\lambda * 0.25\mu\text{m}/\lambda) * (2\lambda * 0.25\mu\text{m}/\lambda) * 0.09\text{fF}/\mu\text{m}^2 + \\ &\quad (6\lambda + 2\lambda + 6\lambda + 2\lambda) * 0.25\mu\text{m}/\lambda * 0.04\text{fF}/\mu\text{m} \\ &= 0.675\text{fF} + 0.16\text{fF} \\ &= 0.84\text{fF} \end{aligned}$$

Example Problems - Parasitic Calculation (8/10)

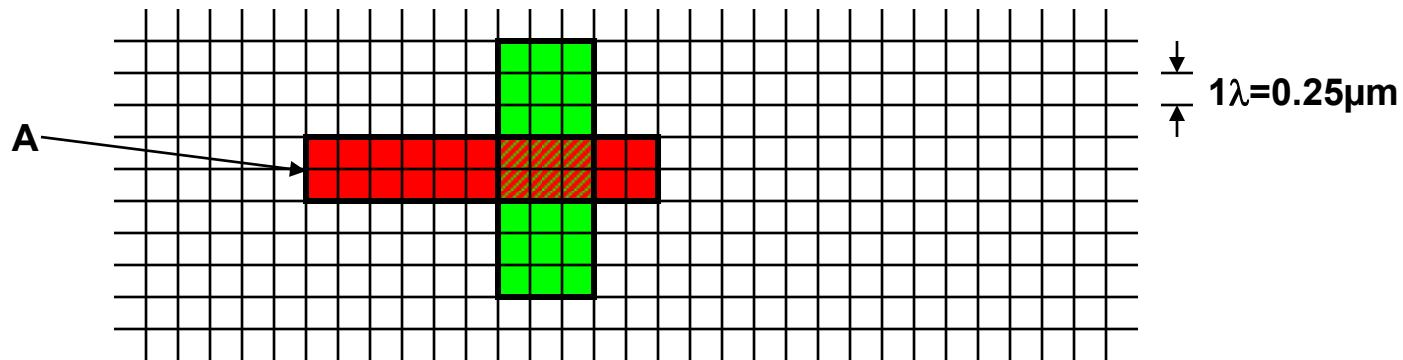


What are the parasitic capacitances visible from point “A”?

$$\begin{aligned} C_{gate} &= (3\lambda * 0.25\mu m/\lambda) * (2\lambda * 0.25\mu m/\lambda) * 0.9 fF/\mu m^2 \\ &= 0.34 fF \end{aligned}$$

Remember: use C_g , not C_{poly} for transistor gates!

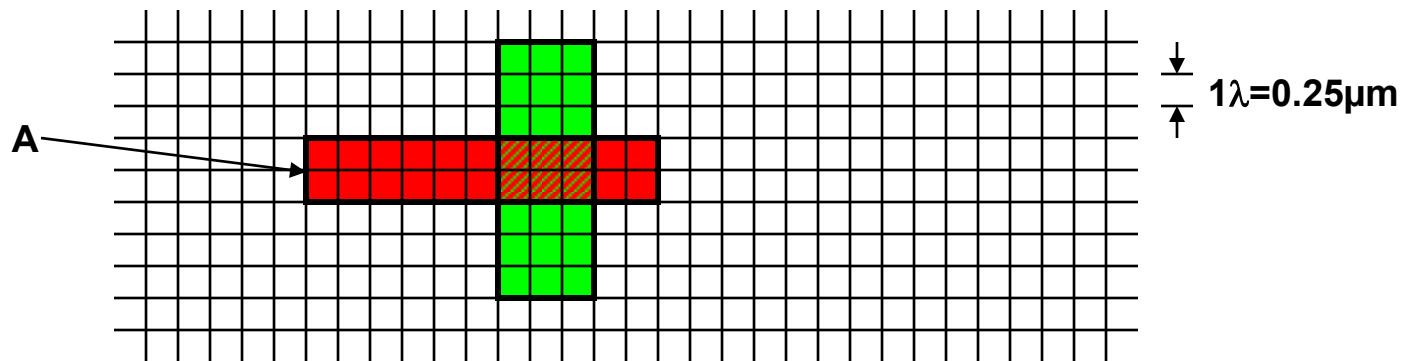
Example Problems - Parasitic Calculation (9/10)



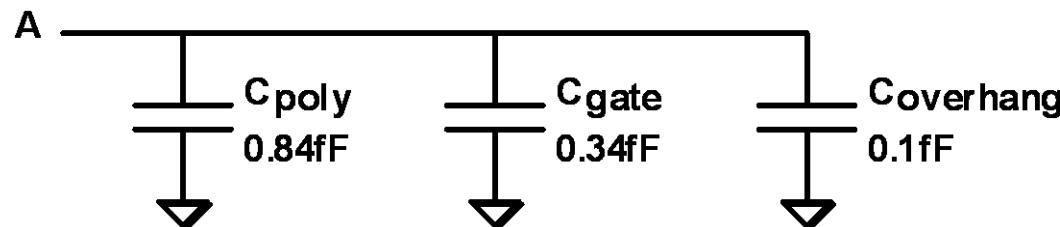
What are the parasitic capacitances visible from point “A”?

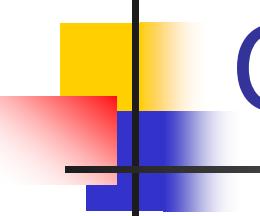
$$\begin{aligned} C_{\text{overhang}} &= (2\lambda * 0.25\mu\text{m}/\lambda) * (2\lambda * 0.25\mu\text{m}/\lambda) * 0.09\text{fF}/\mu\text{m}^2 + \\ &\quad (2\lambda + 2\lambda + 2\lambda + 2\lambda) * 0.25\mu\text{m}/\lambda * 0.04\text{fF}/\mu\text{m} \\ &= 0.0225\text{fF} + 0.08\text{fF} \\ &= 0.1\text{fF} \end{aligned}$$

Example Problems - Parasitic Calculation (10/10)



What are the parasitic capacitances visible from point “A”?





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Inductance estimation

- Inductance is normally small but as the process shrink on-chip inductance must be taken into account.
- Bond-wire inductance can cause deleterious effects in large, high speed I/O buffers.
- The inductance of bonding wires and the pins on packages could be calculated by,

Design techniques to overcome this problem:

- ✓ separate power pins for I/O pads and chip core
- ✓ multiple power and ground pins
- ✓ careful selection of the position of the power and ground pins on the package
- ✓ adding decoupling capacitances on the board
- ✓ increase the rise and fall times
- ✓ use advanced package technologies (SMD, etc)

